



INNOVATIVE SOLUTIONS FOR CRITICAL ENVIRONMENTS

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## CERTIFICATE OF ANALYSIS

|                              |                                             |
|------------------------------|---------------------------------------------|
| <b>Product Category:</b>     | Gloves                                      |
| <b>Substrate Material:</b>   | Nitrile                                     |
| <b>Part Number:</b>          | VTGNCRBTIO2F12-XL                           |
| <b>Lot Number:</b>           | 250118-N038                                 |
| <b>Sample Received Date:</b> | 01-22-2025                                  |
| <b>Manufacturing Date:</b>   | 01-18-2025                                  |
| <b>Test Date:</b>            | 01-25-2025                                  |
| <b>Expiry Date:</b>          | 01-18-2030 *Subject to storage and handling |

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\*Should not be exposed to direct sunlight, UV, light, high temperature, moisture and stored at well ventilated area.

### Physical Inspection

#### Test Method: ASTM D5151 & ASTM D6319

| 1. Water Tight Test  | Sampling | AQL | Result |
|----------------------|----------|-----|--------|
|                      | G1       | 1.5 | Pass   |
| 2. Visual Inspection | Sampling | AQL | Result |
| Critical Defects     | G1       | 1.5 | Pass   |
| Major Defects        | G1       | 2.5 | Pass   |
| Minor Defects        | G1       | 4.0 | Pass   |
| 3. Dimension Test    | Sampling | AQL | Result |
| Length               | S2       | 4.0 | Pass   |
| Thickness            | S2       | 4.0 | Pass   |

### Physical Properties

| Physical Test       | Method    | Criteria    | Actual | Result |
|---------------------|-----------|-------------|--------|--------|
| 4. Tensile Strength | ASTM D412 | Min. 14 Mpa | 23.00  | Pass   |
| 5. Elongation       | ASTM D412 | min. 500%   | 661    | Pass   |

### Cleanliness

#### Liquid Particle Count Test

| LPC                                        | Method          | Specification | Actual | Result |
|--------------------------------------------|-----------------|---------------|--------|--------|
| Counts / cm <sup>2</sup><br>(≥ 0.5 micron) | IEST-RP-CC005.4 | <600          | 420.83 | Pass   |

## Contamination Detection

### Fourier Transform Infra-Red Test

| FTIR                 | Method          | Specification | Actual | Result |
|----------------------|-----------------|---------------|--------|--------|
| Silicone, Amide, DOP | IEST-RP-CC005.4 | Absent        | Absent | Pass   |

### Total Non Volatile Residue Test

| TNVR                                      | Method          | Specification | Actual | Result |
|-------------------------------------------|-----------------|---------------|--------|--------|
| Isopropyl Alcohol (mg/cm <sup>2</sup> )   | IEST-RP-CC005.4 | < 5.0         | 4.00   | Pass   |
| DI H <sub>2</sub> O (mg/cm <sup>2</sup> ) | IEST-RP-CC005.4 | < 2.0         | 0.90   | Pass   |

### Extractable Ions Test (µg/cm<sup>2</sup>):

| Ionic(Anions) | Method          | F <sup>-</sup> | Br <sup>-</sup> | Cl <sup>-</sup> | NO <sub>2</sub> <sup>-</sup> | NO <sub>3</sub> <sup>-</sup> | SO <sub>4</sub> <sup>2-</sup> | PO <sub>4</sub> <sup>3-</sup> | Result |
|---------------|-----------------|----------------|-----------------|-----------------|------------------------------|------------------------------|-------------------------------|-------------------------------|--------|
| Specification | IEST-RP-CC005.4 | < 0.001        | < 0.001         | < 0.20          | < 0.001                      | < 0.12                       | < 0.06                        | < 0.002                       |        |
| Result        | Actual          | ND             | ND              | 0.127           | ND                           | 0.098                        | 0.023                         | ND                            | Pass   |

| Ionic(Cations) | Method          | Na <sup>+</sup> | K <sup>+</sup> | Ca <sup>2+</sup> | Mg <sup>2+</sup> | Li <sup>+</sup> | NH <sub>4</sub> <sup>+</sup> | Result |
|----------------|-----------------|-----------------|----------------|------------------|------------------|-----------------|------------------------------|--------|
| Specification  | IEST-RP-CC005.4 | < 0.02          | < 0.02         | < 0.30           | < 0.005          | < 0.005         | < 0.005                      |        |
| Result         | Actual          | 0.011           | 0.011          | 0.191            | ND               | ND              | ND                           | Pass   |

| Ionic (Heavy metal) | Method          | Al <sup>3+</sup> | Fe <sup>3+</sup> | Cu <sup>2+</sup> | Zn <sup>2+</sup> | Result |
|---------------------|-----------------|------------------|------------------|------------------|------------------|--------|
| Specification       | IEST-RP-CC005.4 | < 0.01           | < 0.005          | < 0.0004         | < 0.07           |        |
| Result              | Actual          | 0.006            | 0.003            | ND               | 0.037            | Pass   |

## Electrical Properties

### Electrostatic Decay

| ESD                           | Method         | Specification          | Actual                 | Result |
|-------------------------------|----------------|------------------------|------------------------|--------|
| Surface Resistance (ohms)     | ESD/EOS S11.11 | < 1 x 10 <sup>11</sup> | 8.2 x 10 <sup>10</sup> | Pass   |
| Static Decay Time (seconds)   |                | < 5.0                  | 0.8                    | Pass   |
| Tribo Electric Charge (volts) |                | < 50                   | 40                     | Pass   |

Notes:



Tested by:  
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